

URSF05G49-1P, URSF05G49-3P, URSF05G49-5P

LOW POWER SWITCHING AND CONTROL APPLICATIONS

- Repetitive Peak Off-State Voltage: $V_{DRM} = 400\text{ V}$
Repetitive Peak Reverse Voltage: $V_{RRM} = 400\text{ V}$
- Average On-State Current: $I_T(AV) = 500\text{ mA}$
- Reduce a Quantity of Parts and Manufacturing Process Because of Built-in RGK: RGK = 1k Ω , 2.7k Ω , 5.1k Ω (Typ.)

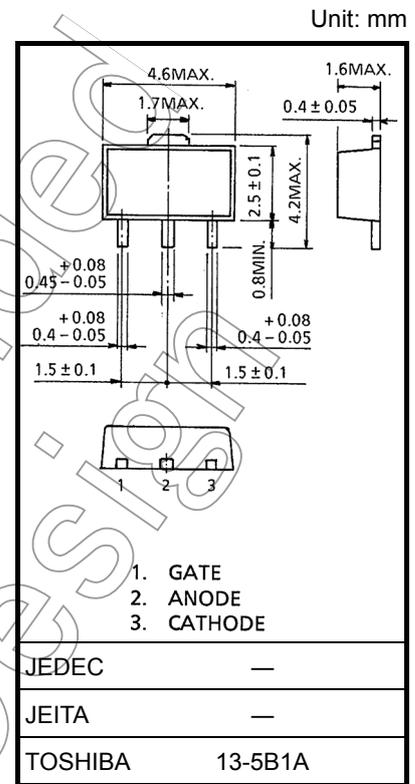
ABSOLUTE MAXIMUM RATINGS

CHARACTERISTIC	SYMBOL	RATINGS	UNIT
Repetitive Peak Off-State Voltage and Repetitive Peak Reverse Voltage	V_{DRM} V_{RRM}	400	V
Non-Repetitive Peak Reverse Voltage (Non-Repetitive<5ms, $T_j = 0\sim 125^\circ\text{C}$)	V_{RSM}	500	V
Average On-State Current (Half Sine Waveform)	$I_T(AV)$	500	mA
R.M.S On-State Current	$I_T(RMS)$	800	mA
Peak One Cycle Surge On-State Current (Non-Repetitive)	I_{TSM}	9 (50Hz)	A
		10 (60Hz)	
I^2t Limit Value	I^2t	0.4	A^2s
Critical Rate of Rise of On-State Current (Note 1)	di/dt	10	$\text{A}/\mu\text{s}$
Peak Gate Power Dissipation	P_{GM}	0.1	W
Average Gate Power Dissipation	$P_{G(AV)}$	0.01	W
Peak Forward Gate Voltage	V_{FGM}	3.5	V
Peak Reverse Gate Voltage	V_{RGM}	-5	V
Peak Forward Gate Current	I_{GM}	125	mA
Junction Temperature	T_j	-40~125	$^\circ\text{C}$
Storage Temperature Range	T_{stg}	-40~125	$^\circ\text{C}$

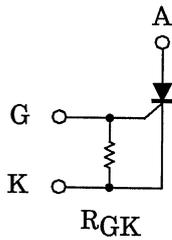
Note 1: di/dt Test condition
 $i_G = 5\text{mA}$, $t_{gw} = 10\mu\text{s}$,
 $t_{gr} = 250\text{ns}$

Note 2: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).



EQUIVALENT CIRCUIT

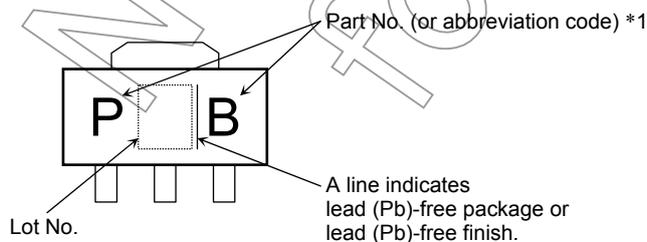


ELECTRICAL CHARACTERISTICS (Ta = 25°C)

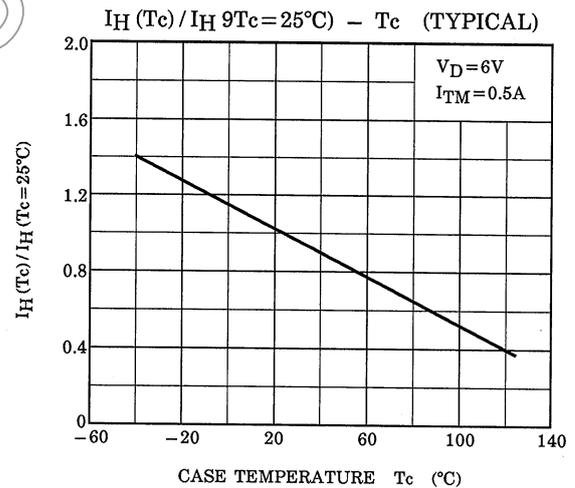
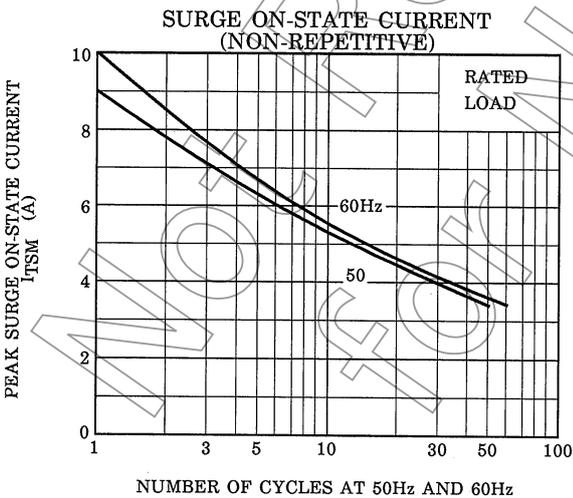
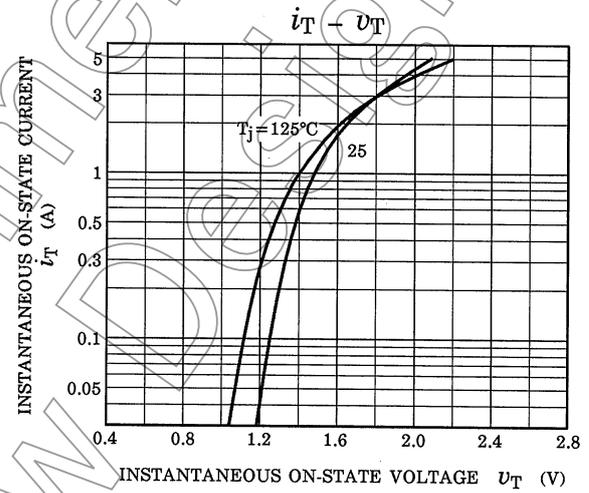
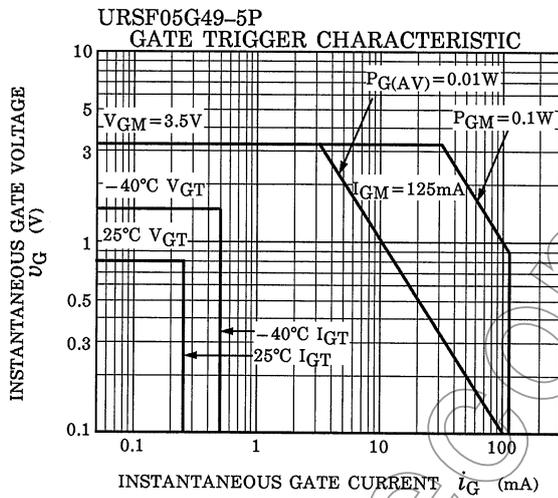
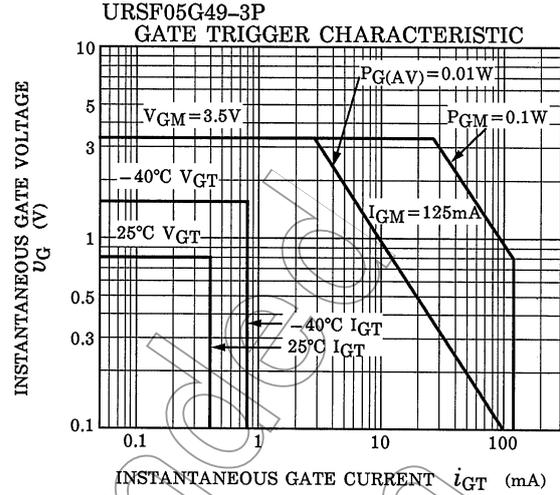
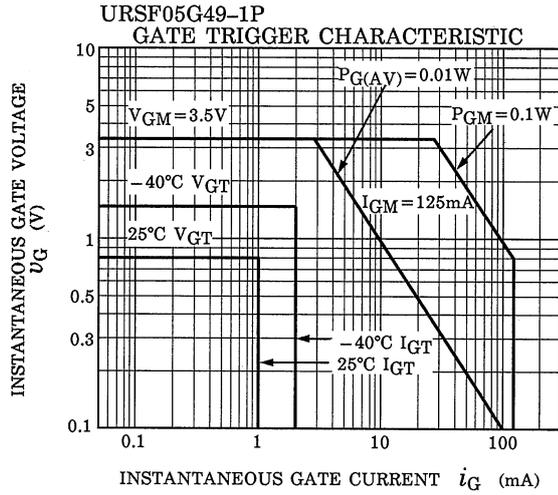
CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN	TYP.	MAX	UNIT
Repetitive Peak Off-State Current and Repetitive Peak Reverse Current		I_{DRM} I_{RRM}	$V_{DRM} = V_{RRM} = \text{Rated}$	—	—	10	μA
Peak On-State Voltage		V_{TM}	$I_{TM} = 1\text{A}$	—	—	1.5	V
Gate Trigger Voltage		V_{GT}		—	—	0.8	V
Gate Trigger Current	URSF05G49-1P	I_{GT}	$V_D = 6\text{V}, R_L = 100\Omega$	250	700	1000	μA
	URSF05G49-3P			100	250	400	
	URSF05G49-5P			50	160	250	
Holding Current	URSF05G49-1P	I_H	$I_{TM} = 500\text{mA}, V_D = 6\text{V}$	—	—	6	mA
	URSF05G49-3P			—	—	3	
	URSF05G49-5P			—	—	2	
Resistor Between Gate and Cathode	URSF05G49-1P	R_{GK}	—	700	1000	1300	Ω
	URSF05G49-3P			1890	2700	3510	
	URSF05G49-5P			3570	5100	6630	
Critical Rate of Rise of Off-State Voltage	URSF05G49-1P	dv/dt	$V_{DRM} = \text{Rated}, \text{Exponential Rise}$	—	200	—	V / μs
	URSF05G49-3P			—	70	—	
	URSF05G49-5P			—	40	—	
Turn-On Time		t_{gt}	$V_D = \text{Rated}, i_G = 5\text{mA}$	—	—	1.5	μs
Thermal Resistance		$R_{th(j-a)}$	Junction to Ambient	—	—	70	$^{\circ}\text{C} / \text{W}$

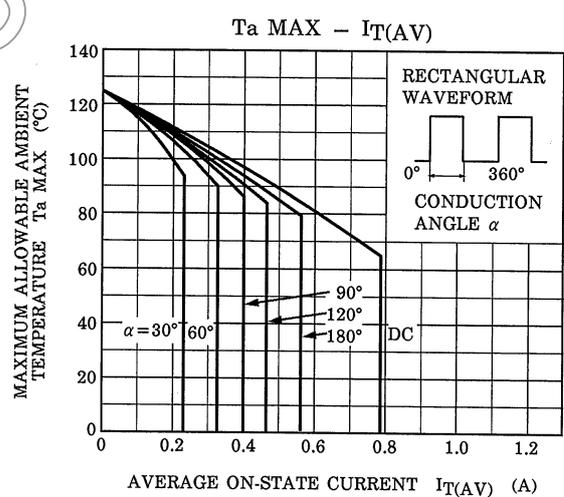
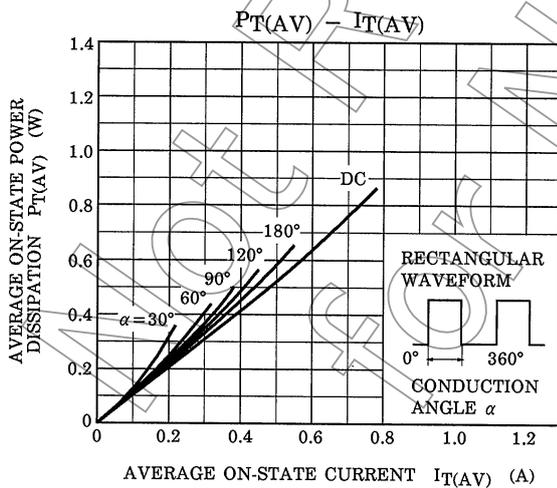
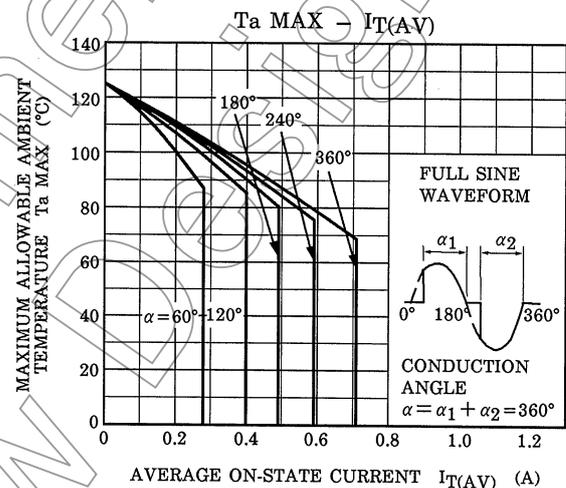
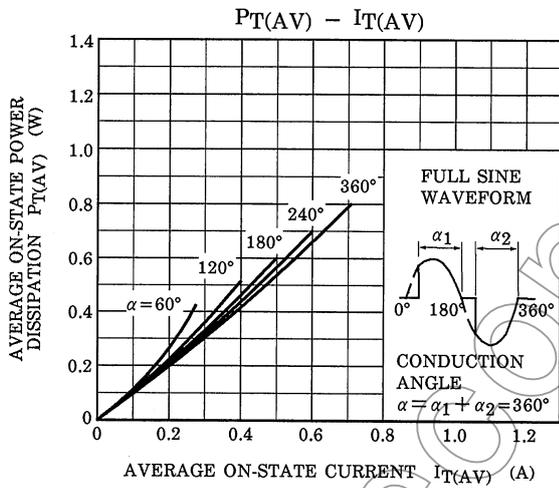
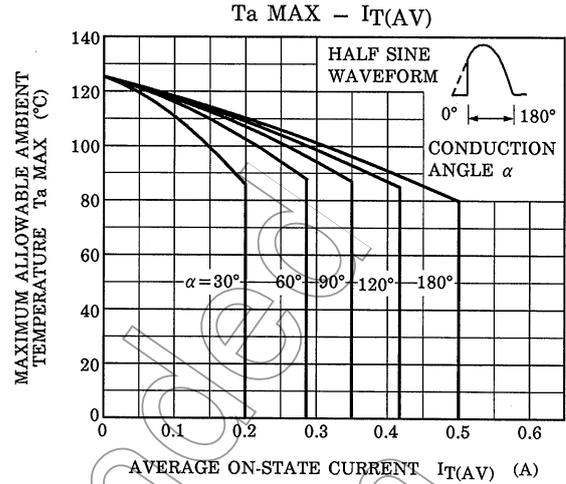
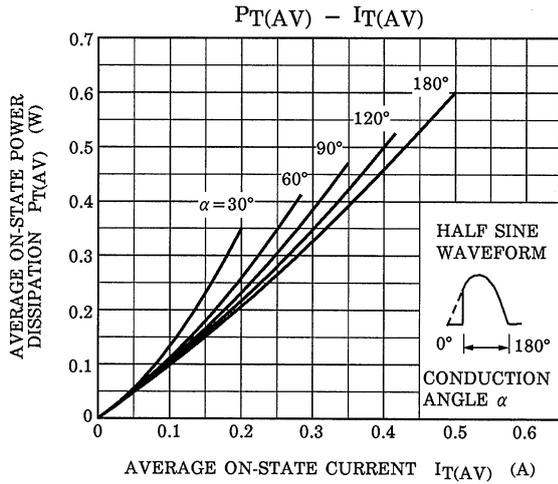
Note: Thermal Resistance Test Condition
Use 0.6×30×30mm Alumina Plate

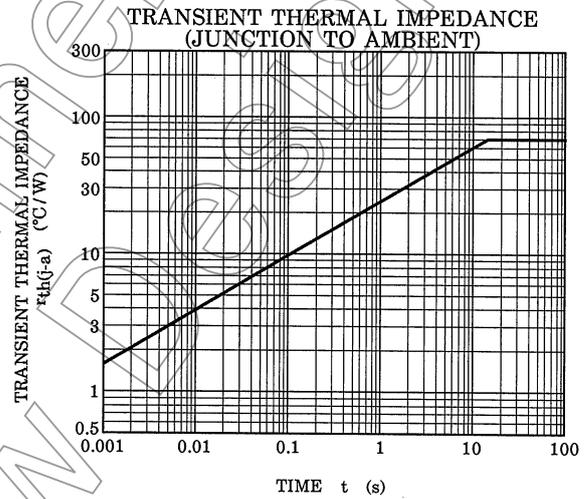
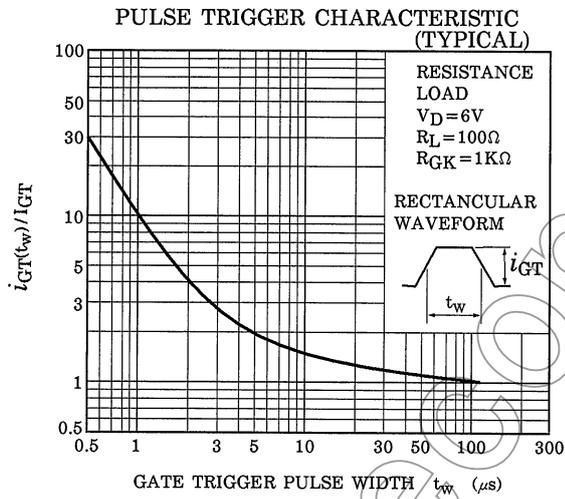
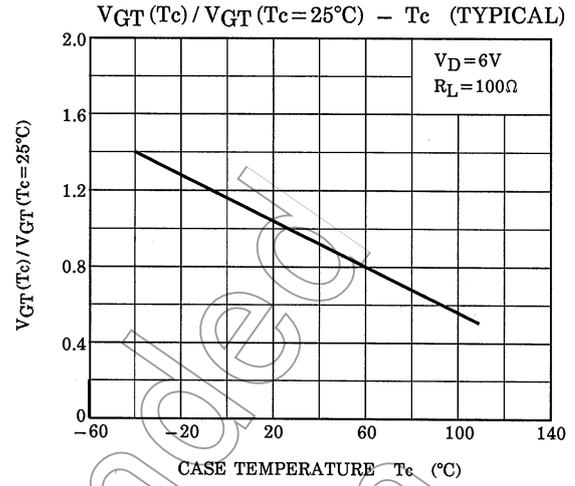
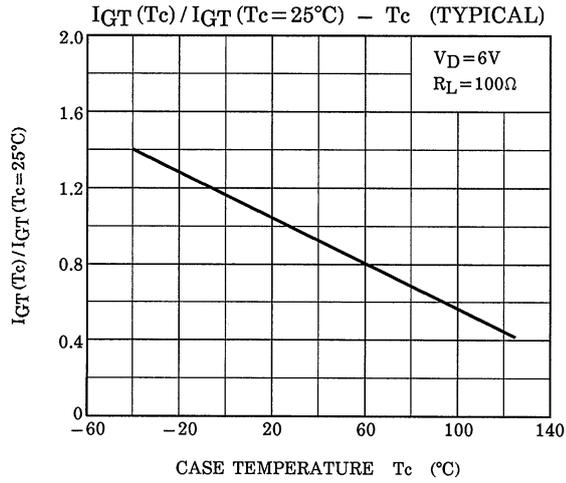
MARKING



	Part No. (or abbreviation code)	Part No.
	*1	PB
	PC	URSF05G49-3P
	PD	URSF05G49-5P







Not Recommended for New Design

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20070701-EN

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